What is claimed is:

1.   A BISR mode for testing memory, said BISR mode comprising: means for testing all redundant elements of the memory including the ones which are not used; and means for checking interaction between redundant elements of the memory and adjacent functional memory.

2.   A BISR mode as recited in claim 1, further comprising means for using repair information to repair the memory.

3.   A BISR mode as recited in claim 1, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the memory.

4.   A BISR mode as recited in claim 3, wherein the means for forcing usage of redundant elements which are not needed to be used for repairing the memory comprises means for faking defects to remap good elements with redundant elements.

5.   A BISR mode as recited in claim 2, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the memory.

6.   A BISR mode as recited in claim 5, wherein the means for forcing usage of redundant elements which are not needed to be used for repairing the memory comprises means for faking defects to remap good elements with redundant elements.

7.   A BISR mode as recited in claim 1, further comprising means for forcing usage of all redundant elements of the memory.

8.   A method for testing memory, said method comprising: testing all redundant elements of the memory including the ones which are not used; and checking interaction between all redundant elements of the memory and adjacent functional memory.

9.   A method as recited in claim 8, further comprising using repair information to repair the memory.

10.   A method as recited in claim 8, further comprising forcing usage of redundant elements which are not needed to be used for repairing the memory.

11.   A method as recited in claim 10, wherein the step of forcing usage of redundant elements which are not needed to be used for repairing the memory comprises faking defects to remap good elements with redundant elements.

12.   A method as recited in claim 9, further comprising forcing usage of redundant elements which are not needed to be used for repairing the memory.

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13.   A method as recited in claim 12, wherein the step of forcing usage of

redundant elements which are not needed to be used for repairing the memory

comprises faking defects to remap good elements with redundant elements.

14.   A method as recited in claim 8, further comprising forcing usage of all

5   redundant elements of the memory.